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Instruments and software used for measurement in high-voltage and high-current tests –

Part 3: Requirements for hardware for tests with alternating and direct voltages and currents

[IEC 61083-3:2020](#)

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Appareils et logiciels utilisés pour les mesurages pendant les essais à haute tension et à courant élevé –

Partie 3: Exigences relatives au matériel pendant les essais avec des tensions et des courants alternatifs et continus



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**Instruments and software used for measurement in high-voltage and high-current tests –
Part 3: Requirements for hardware for tests with alternating and direct voltages and currents**

[IEC 61083-3:2020](#)

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Partie 3: Exigences relatives au matériel pendant les essais avec des tensions et des courants alternatifs et continus

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INTERNATIONAL ELECTROTECHNICAL COMMISSION

**INSTRUMENTS AND SOFTWARE USED FOR MEASUREMENT
IN HIGH-VOLTAGE AND HIGH-CURRENT TESTS –**
**Part 3: Requirements for hardware for tests with alternating
and direct voltages and currents**

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The text of this International Standard is based on the following documents:

FDIS	Report on voting
42/380/FDIS	42/387/RVD

Full information on the voting for the approval of this International Standard can be found in the report on voting indicated in the above table.

This document has been drafted in accordance with the ISO/IEC Directives, Part 2.

A list of all parts in the IEC 61083 series, published under the general title *Instruments and software used for measurement in high-voltage and high-current tests*, can be found on the IEC website.

Future standards in this series will carry the new general title as cited above. Titles of existing standards in this series will be updated at the time of the next edition.

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INTRODUCTION

The electric power industry requires standardized tools to provide confidence in testing results, and to prove equivalence between tests performed in different laboratories and test fields.

This part of IEC 61083 specifies requirements for the performance of digital recording instruments used for tests with alternating and direct voltages and currents.

The intention of this document is to provide recommendations on the digital recording instruments to be used in tests with alternating and direct voltages and currents.

Digital recording instruments are considered as black boxes (including hardware, firmware, and software). They are characterized for their intended application by physical calibration with the waveforms needed for that application.

This document does not apply to simple analogue or digital meters that do not have recording capability.

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INSTRUMENTS AND SOFTWARE USED FOR MEASUREMENT IN HIGH-VOLTAGE AND HIGH-CURRENT TESTS –

Part 3: Requirements for hardware for tests with alternating and direct voltages and currents

1 Scope

This part of IEC 61083 is applicable to digital recording instruments used for measurements during tests with high alternating and direct voltages and currents. It specifies the measuring characteristics and calibrations required to meet the measuring uncertainties and procedures specified in the relevant IEC standards (e.g. IEC 60060-1, IEC 60060-2, IEC 60060-3, IEC 62475, IEC 61180).

This document is applicable to those digital recording instruments that will be designed and type tested according to this document.

This document

- defines performance requirements for digital recording instruments used during tests with alternating voltages and currents (AC) or direct voltages and currents (DC);
- specifies the necessary requirements for such instruments to ensure their suitability for use under the relevant standards;
- establishes the tests and procedures necessary to demonstrate their compliance;
- defines the terms related to digital recording instruments with recording function and access to raw data.

NOTE Examples of relevant alternating and direct voltages and currents to be measured are listed in Annex D.

This International Standard has the status of a horizontal standard in accordance with IEC Guide 108.

2 Normative references

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC 60060-2, *High-voltage test techniques – Part 2: Measuring systems*

IEC 61180, *High-voltage test techniques for low-voltage equipment – Definitions, test and procedure requirements, test equipment*

IEC 62475, *High-current test techniques – Definitions and requirements for test currents and measuring systems*

ISO/IEC Guide 98-3:2008, *Uncertainty of measurement – Part 3: Guide to the expression of uncertainty in measurement (GUM:1995)*

3 Terms and definitions

For the purposes of this document, the following terms and definitions apply.

ISO and IEC maintain terminological databases for use in standardization at the following addresses:

- IEC Electropedia: available at <http://www.electropedia.org/>
- ISO Online browsing platform: available at <http://www.iso.org/obp>

3.1 Digital recording instruments

3.1.1

approved instrument

measuring device that is shown to comply with the requirements set out in IEC 61083-3

3.1.2

digital recording instrument

device with digital output capability of the recorded input

Note 1 to entry: This definition includes digital recorders, digital oscilloscopes, digital peak voltmeters and other digital recording instruments if applicable.

Note 2 to entry: The waveform of the digital record is usually displayed on a screen, plotted or printed. This process may change the appearance of the waveform due to the processing involved.

3.1.3

assigned measurement range (standards.iteh.ai)

range of input voltage for which the digital recording instrument can be used within the uncertainty limits given in IEC 61083-3

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3.1.4

output

displayed (in any way) value of a digital recording instrument at a specific instant or the numerical value of a digital recording instrument recorded at a specific instant

3.1.5

full-scale deflection

minimum input value, which produces the nominal maximum output of the digital recording instrument in the specified range

3.1.6

offset

output of a digital recording instrument for zero input

3.1.7

raw data

original record of sampled and quantized information obtained when a digital recording instrument converts an analogue signal into a digital form, with the correction of the output for offset and multiplying the record by a constant factor being permitted

3.1.8

test duration

range of a time interval in which the measurement is done

3.1.9

reading rate

rate with which the instrument displays or stores the readings of the measured AC or DC voltage or current

Note 1 to entry: In sampling instruments, readings are calculated e.g. by averaging (DC) or by calculating the RMS value (AC) of several samples.

3.2 Rated values

3.2.1 rated resolution

r

reciprocal of two to the power of the rated number of bits N of the A/D converter, defined as

$$r = 2^{-N}$$

3.2.2 sampling rate

number of samples taken per unit of time

3.2.3 record length

duration of the record expressed either in a time unit or as the total number of samples

3.2.4 warm-up time

time interval from when an instrument is first switched on to when an instrument meets operational requirements

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3.3 Factors

3.3.1 scale factor

factor by which the output corrected for offset is multiplied in order to determine the measured value of the input quantity

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Note 1 to entry: Scale factor includes the ratio of any built-in or external attenuator and is determined by calibration.

3.3.2 static scale factor

scale factor for a direct voltage or a direct current input

3.3.3 non-linearity of amplitude

deviation of the actual output of a digital recording instrument from the nominal value, which is determined by dividing the input voltage or input current by the scale factor

Note 1 to entry: The static non-linearity for a DC input voltage or current is different from the non-linearity under dynamic conditions.

3.3.4 peak factor

numerical value calculated from the peak value divided by the RMS value of a measurement

3.4 Dynamic performance

3.4.1 integral non-linearity

$s(k)$

difference between corresponding points on the measured quantization characteristic and on the ideal quantization characteristic that is based on the static scale factor

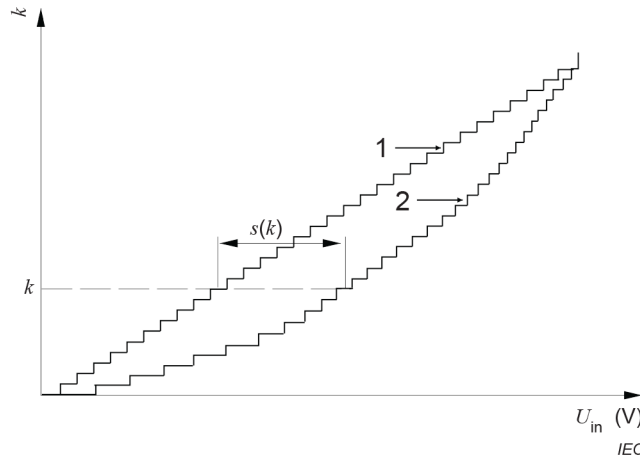
SEE: Figure 1.

**3.4.2
quantization characteristic**

characteristic showing the relationship between the output of the digital recording instrument and the direct voltage on the input which produces this output

SEE: Figure 1.

Note 1 to entry: The average slope of the quantization characteristic is equal to the reciprocal of the static scale factor of the A/D converter.



Curve 1: Quantization characteristic of an ideal 5-bit digital recording instrument.

Curve 2: Quantization characteristic of a non-linear 5-bit digital recording instrument (the low resolution of 5 bits has been chosen to clarify the illustration).

Figure 1 – Integral non-linearity $s(k)$ at code k
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**3.4.3
code k**

integer used to identify a digital level

**3.4.4
code bin width**

$w(k)$
range of input voltage or input current allocated to code k

SEE: Figure 2.

**3.4.5
average code bin width**

w_0
product of the full-scale deflection and the rated resolution

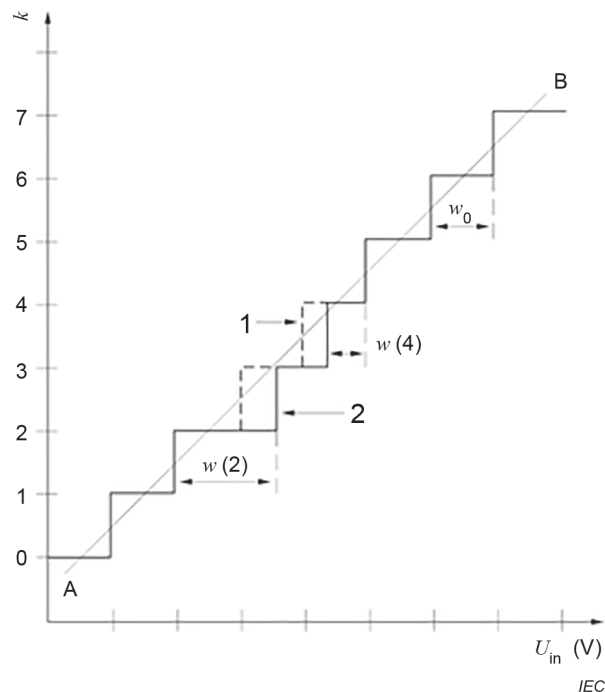
SEE: Figure 2.

Note 1 to entry: The average code bin width is approximately equal to the static scale factor.

**3.4.6
differential non-linearity**

$d(k)$
difference between a measured code bin width $w(k)$ for code k and the average code bin width w_0 divided by the average code bin width w_0

$$d(k) = \frac{w(k) - w_0}{w_0}$$



Curve 1: Quantization characteristic of an ideal 3-bit digital recording instrument.

Curve 2: Quantization characteristic of a 3 bit digital recording instrument showing large $d(k)$ at codes $k = 2, 3$ and 4.

Line AB: A straight line joining the midpoints of the code bins of an ideal instrument (the low resolution of 3 bits has been chosen to clarify the illustration).

Figure 2 – Non-linearity $d(k)$ and code bin width $w(k)$ under DC conditions

3.4.7 rise time

t_R

time interval within which the response to an applied step passes from 10 % to 90 % of its steady-state amplitude

3.4.8 time base

unit of the digital recording instrument horizontal scale against which a time interval is measured

3.5 Uncertainties

3.5.1 uncertainty

parameter, associated with the result of a measurement, that characterizes the dispersion of the values that could reasonably be attributed to the measurand

Note 1 to entry: Uncertainty is positive and given without sign.

Note 2 to entry: Uncertainty of measurement should not be confused with the tolerance of the test value.

3.5.2 standard uncertainty

uncertainty of the result of a measurement expressed as a standard deviation

[SOURCE: ISO/IEC Guide 98-3:2008, 2.3.1]

3.6 Tests

3.6.1

calibration

set of operations that establishes, by reference to standards, the relationship which exists, under specified conditions, between an indication and a result of a measurement

[SOURCE: IEC 60050-311:2001, 311-01-09, modified – The notes have been deleted.]

3.6.2

type test

conformity test made on one or more items representative of the production

Note 1 to entry: For a measuring system, this is understood as a test performed on a component or on a complete measuring system of the same design to characterize it under operating conditions.

[Source: IEC 60050-151:2001, 151-16-16, modified – The note has been added.]

3.6.3

routine test

conformity test made on each individual item during or after manufacture

Note 1 to entry: This is understood as a test performed on each component or on each complete measuring system to characterize it under operating conditions.

[Source: IEC 60050-151:2001, 151-16-17, modified – The note has been added.]

3.6.4

performance test

test performed on a complete measuring system to characterize it under operating conditions

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3.6.5

performance check

simple procedure to ensure that the most recent performance test is still valid

3.6.6

record of performance

detailed record, established and maintained by the user, describing the measuring system and containing evidence that the requirements given in IEC 61083-3 have been met, which includes the results of the initial performance test and the schedule and results of each subsequent performance test and performance check

4 Operating conditions

The limits of operating conditions given in Table 1 are those under which the digital recording instrument shall operate and meet the uncertainty requirements specified for this instrument.

Table 1 – Operating conditions

Condition	Range
Environment	
Ambient temperature	5 °C to 40 °C
Ambient relative humidity (non-condensing)	10 % to 90 %
Mains power supply	
Supply voltage	Rated voltage ± 10 % (RMS) Rated voltage ± 12 % (AC peak)
Supply frequency	Rated frequency ± 5 %

Any exceptions to the values given in Table 1 shall be explicitly and clearly stated in the record of performance.

NOTE The general requirements for testing electromagnetic compatibility of electrical equipment for measurement, control and laboratory use are described in IEC 61326-1.

5 Calibration and test methods

5.1 Applicability

A digital recording instrument may be qualified for all requirements in this document, or for a suitable subset.

5.2 Qualification of digital recording instruments

Digital recording instruments for measurement of high voltage and/or high current are qualified by comparative measurements against known reference systems traceable to national standards, proving both requirements on accuracy and dynamic performance.

Qualifications are performed both as type tests performed once for each type of instrument and routine tests performed once for each instrument, and calibrations are performed regularly on each instrument.

For electromagnetic interference tests in high-voltage and high-current laboratories and test fields, see recommendations in Annex B.

5.3 Requirements for reference generators

A reference waveform generator is only necessary for calibration when the digital recording instrument contains a measurement device which is to be used as a reference instrument (see 6.3). Otherwise any waveform generator can be used if it fulfils general requirements for amplitude and frequency stability and noise.

NOTE An approved waveform generator can be considered qualified if the amplitude and the frequency are stable within 0,1 % of output and the noise is < 1 % of output.

5.4 Available methods for qualification of digital recording instruments

Calibration (scale factor determination) (5.5),

Dynamic performance tests (5.6.2),

Internal noise (5.6.3),

Interference tests (5.6.4),

Displaying performance (5.6.5).